Institute of Criminology



Triple Risk for Delinquency and Crime Model (TRDm): A New Integrative Theory of Criminal Behaviour

Professor Santiago Redondo

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Institute of Criminology Public Seminar Series

Thursday 17th February 2011, 5.30pm Seminar Room B3, Institute of Criminology, Sidgwick Avenue, Cambridge, CB3 9DA

A drinks reception in the basement foyer will follow this seminar for attendees

The aim of this seminar is to present a theoretical perspective that I am working on, termed the "triple risk for delinquency and crime model" (or TRD). It is based on previous theories on criminal careers, risk factors, social support and crime opportunities. The perspective considers chiefly three sources of risk: a) personal factors, b) deficits in pro-social support, and c) individuals' exposure to crime opportunities. The TRD model asserts that the probability of crime in a particular individual is a function of the interaction among these three sources of risk. A parallel hypothesis is proposed also in relation to the distribution of the social risk of crime. These models are conceived as a general meta-theoretical perspective that is compatible with specific criminogenic processes and theories such as social learning, social-bond breaking, strain and so on.

Santiago Redondo is a Professor of Criminology at the Central University of Barcelona (Spain). He is Principal Researcher of the group, Advanced Studies in Violence (http://www.ub.edu/geav) of this same university. His former positions were as prison psychologist, prison governor, and director of the prison rehabilitation services at the Justice Department of the State of Catalonia (Spain). His current research is in the fields of treatment programmes for offenders, risk assessment, developmental criminology, and criminological theory. He has published numerous papers, book chapters and books on such topics as offender rehabilitation, juvenile delinquency, sex and partner violence, social control, and general criminology.